



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: R. Japp et al

Group Art Unit: : Endicott Interconnect Technologies, Inc.
Examiner: : IP Law, 0099/257-4 AA12
Serial No.: : 1701 North Street
Filed: Herewith : Endicott, New York 13760
Title: Circuitized Substrate, Method of Making
Same, Electrical Assembly Utilizing Same, And
Information Handling System Utilizing Same

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INFORMATION DISCLOSURE STATEMENT/CERTIFICATION

For ensuring compliance with Applicant's/Applicants' duty of disclosure under 37 CFR § 1.56, the undersigned hereby submits the documents listed on the attached Form PTO-1449 for consideration by the Examiner in charge of the above-identified patent application.

The listing of these documents is not to be construed as an admission that such is actually prior art with respect to the invention of the present application and is not to be construed that such is material with respect to the present invention.

[] U.S. patent applications which Applicant/Applicants considers/consider to be related to the above-identified application.



- ☐ A concise explanation of the relevance of the non-English language documents is attached:
- ☐ The relevance of the documents is indicated on the enclosed copy of the _____ Search Report for the priority application _____.

These documents are being submitted (check only one of the next four boxes):

- ☒ within three months of the filing of the above U.S. national application or of the date of entry of the U.S. national stage in an International Patent Application (no fee is due);
- ☐ before receiving a first Office Action on the merits of the above-identified patent application (no fee is due);
- ☐ following receipt of a first Office Action, but before issuance of a Final Office Action or a Notice of Allowance (if this box is checked, the fee box below or one of the last two boxes must be checked);

OR

- ☐ following receipt of a Notice of Allowance or a Final Office Action (if this box is checked, the fee box and one of the last two boxes also must be checked).




CERTIFICATION

- [] The undersigned certifies that each item of this information is being submitted within three months of the date it was first cited in any communication from a foreign patent office in a counterpart foreign application.
- [] The undersigned certifies that no item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned, after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR § 1.56(c) more than three months prior to the filing of this information disclosure statement.

Respectfully submitted,

Dated: 3/30/04
Telephone: 561-575-3608
Fax: 561-745-2741

By: 
Lawrence R. Fraley
Attorney for Applicant/Applicants
Reg. No. 26,885

FORM PTO 1449 (Modified)

LIST OF PATENTS AND
PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENTPage 1 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	AA	3,953,566	04/76	Gore			
	AB	3,962,653	06/76	Basset			
	AC	4,187,390	02/80	Gore			
	AD	4,482,516	11/84	Bowman et al			
	AE	4,579,772	04/86	Bhatt et al			
	AF	4,642,160	02/87	Burgess			
	AG	4,675,789	06/87	Kuwabara et al			
	AH	4,713,137	12/87	Sexton			
	AI	4,783,345	11/88	Kleeberg et al			
	AJ	4,864,722	09/89	Lazzarini et al			
	AK	5,129,142	07/92	Bindra et al			
	AL	5,229,550	07/93	Bindra et al			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM						
	AN						
	AO						
	AP						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

FORM PTO 1449 (Modified)

LIST OF PATENTS AND
PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENTPage 2 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	AA	5,246,817	09/93	Shipley			
	AB	5,368,921	11/94	Ishii et al			
	AC	5,376,453	12/94	von Gentzkow et al			
	AD	5,418,689	05/95	Alpaugh et al			
	AE	5,483,101	01/96	Shimoto et al			
	AF	5,565,267	10/96	Capote et al			
	AG	5,648,171	07/97	von Gentzkow et al			
	AH	5,652,055	07/97	King et al			
	AI	5,670,262	09/97	Dalman			
	AJ	5,677,045	10/97	Nagai et al			
	AK	5,685,070	11/97	Alpaugh et al			
	AL	5,726,863	03/88	Nakayama et al			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM						
	AN						
	AO						
	AP						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

FORM PTO 1449 (Modified)

LIST OF PATENTS AND
PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENT

Page 3 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	AA	5,814,405	09/98	Branca et al			
	AB	5,981,880	11/99	Appelt et al			
	AC	6,018,196	01/00	Noddin			
	AD	6,042,685	03/00	Shinada et al			
	AE	6,119,338	09/00	Wang et al			
	AF	6,143,401	11/00	Fischer			
	AG	6,207,595 B1	03/01	Appelt et al			
	AH	6,212,769 B1	04/01	Boyko et al			
	AI	6,248,959 B1	06/01	Sylvester			
	AJ	6,291,779 B1	09/01	Lubert et al			
	AK	6,323,436 B1	11/01	Hedrick et al			
	AL	6,378,201 B1	04/02	Tsukada et al			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM						
	AN						
	AO						
	AP						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED

FORM PTO 1449 (Modified)

LIST OF PATENTS AND
PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENT

Page 4 of 5

ATTY. DOCKET NO.	EI-2-04-003	SERIAL NO.	N/A
APPLICANT R. Japp et al			
FILING DATE	HEREWITH	GROUP	N/A

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILI NG
	AA	6,405,431 B1	06/02	Shin et al			
	AB	6,506,979 B1	01/03	Shelnut et al			
	AC	6,541,589 B1	04/03	Baillie			
	AD	6,586,687 B2	07/03	Lee et al			
	AE	US2002/0150673	10/02	Thorn et al			
	AF	US2002/0170827	11/02	Furuya			
	AG	US2002/0172019	11/02	Suzuki et al			
	AH	US2002/0190378	12/02	Hus et al			
	AI	US2003/0022013	01/03	Japp et al			
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM	JP 56049271	05/81	Japan			Abstract
	AN	JP 7086710	03/95	Japan			Abstract
	AO	JP 7097466	04/95	Japan			Abstract
	AP	JP 8092394	04/96	Japan			Abstract

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER	DATE CONSIDERED
----------	-----------------

FORM PTO 1449 (Modified)

LIST OF PATENTS AND
PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENTPage 5 of 5

ATTY. DOCKET NO. EI-2-04-003

SERIAL NO.

N/A

APPLICANT R. Japp et al

FILING DATE

HEREWITH

GROUP

N/A

U. S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILI NG
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLAT ION
	AM	JP2001015912A2	01/01	Japan			Abstract
	AN	JP2002223070A2	08/02	Japan			Abstract
	AO						
	AP						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER

DATE CONSIDERED